Mitsui Chemicals India Pvt. Ltd.

ULR No. : TC890623000000049F

DOC No. : MCIND/2023/LB/049.V1 Plot 5 and 6, Swastik Industrial Estate, Vill: Sari, Tal: Telephone : +91 9871742221 Sanand, Ahmedabad, Ahmadabad, Gujarat, India -

FAX : 41204299 382220

E-Mail : <u>puneet.kumar@mitsuic</u>

<u>hemicals.com</u>

BO Code : NA

Test REPORT AS PER: IS 14286 (2010)

QR Code/Barcode: 129186CRS

REPORT NO: SC22SPI00961_1 DATE: 02 Aug, 2023

PART A. PARTICULARS OF SAMPLE SUBMITTED

a) Customer Name & Address : NOVASYS GREENERGY PRIVATE LIMITED

KHASRA NO. 185, MOUZA: MAHALGAON, TAHSIL: KAMPTEE, NAGPUR-441202, MAHARASHTRA, INDIA, NA, MAHARASHTRA, India - 441202

b) Nature of sample : -

c) Grade/Variety/Type/Class Size etc : NA

d) Declare values, if any : -

e) Batch No. & Date of Manufacture : /
f) Quantity : 8

g) Date of Receipt : 01 Dec, 2022

h) BIS Seali) IO's Signaturei: Verified by Sample Cell

j) Any other Information / Expiry Date, If any : /

k) Date of Commencement of Testing : 01 Aug, 2023

I) Date of Completion of Testing : 02 Aug, 2023

m) Section Code : 22E1444N

n) Section Report No. : 22E1444N_1

o) Report Type : New

p) Reference Report No.

q) Remarks : Please refer attached test report

Vinay Singh OIC SAMPLE CELL (Authorized Signatory) Authorized on: 02 Aug, 2023 19:34 PM

1. Mitsui Chemicals India Pvt. Ltd.

IS 14286 (2010)

PART B. SUPPLEMENTARY INFORMATION

1. Reference to sampling procedure, wherever applicable.

Not Applicable

2. Supporting documents for the measurements taken and results derived like graphs, table sketches and or photographs as appropriate to test report, if any.

Yes

3. Deviation from the test methods as prescribed in relevant ISS/Work instruction, if any. Not Applicable

3. NABL Report required?

Yes

Vinay Singh OIC Electrical (Authorized Signatory) Authorized on: 02 Aug, 2023 19:32 PM

PART C. TEST RESULT

S.No.	Clause No Table No. Sl. No	Parameter - Method of test	Test Description	Min Limit	Max Limit	Unit	Result/ Observation
1	10.18	Bypass diode thermal' test	-	-	-	-	75.5°C (Panjit Semi Conductor.). The diode junction temperature did not exceed the diode manufacturer's maximum junction temperature limit. and the samples me the following requirements, 1. Visual Inspection test, No Visual defects found 2. Maximum power determination Power determination Power degradation≤ 5% 3. Insulation test - The measured insulation resistance was not less than 15.5 MΩ. For more details, please refer test report.
2	10.17	Hail test				-	The Hail test was completed on 19/01/2023. There was no evidence of mechanical damage during the test and the samples met the following requirements, 1. Visual Inspection tes No Visual defects found 2. Maximum power determination Power degradation ≤5% 3. Insulation test -The measured insulation resistance was not less than 15.5 MΩ. For more details, please refer test report
3	10.16	Mechanical load test	-	-	-	-	The mechanical load test was completed on 18/01/2023. There was no damage after the test, and the samples met the following requirements, 1. Visual Inspection test No Visual defects found 2. Maximum power determination power degradation≤5% 3. Insulation test -The measured insulation resistance was not less than 15.5 MΩ. For more details please refer test report.

4	10.75	Wet Inc.					Allel
4	10.15	Wet leakage current test	-	-	-	-	All the modules passed the initial and final wet leakage current test. For more details, please refer to the test report
5	10.14	Robustness of termination test			-		Test date: 05/01/2023. There was no evidence of a major defect after the Robustness of the termination Test and the samples met the following requirements, 1. Visual Inspection test. No Visual defects found 2. Maximum power determination, Power degradation ≤ 5% 3. Insulation test- The measured insulation resistance was not less than 15.5 MΩ.For more details, please refer test report
6	10.13	Damp heat test					There was no evidence of a major defect after the Damp Heat Test and the samples met the following requirements, 1. Visual Inspection test. No Visual defects found 2. Maximum power determination, Power degradation≤5% 3. Insulation test- The measured insulation resistance was not less than 15.5 MΩ 4. Wet Leakage current test- The measured insulation resistance was not less than 15.5MΩ. For more details, please refer test report.
7	10.12	Humidity freeze test				-	There was no evidence of a major defect after the Humidity Freeze Test and the samples met the following requirements, 1. Visual Inspection test. No Visual defects found 2. Maximum power determination, Power degradation≤5% 3. Insulation test- The measured insulation resistance was not less than 15.5 MΩ. For more details, please refer test report.

8	10.11	Thermal cycling test		-		-	There was no evidence of a major defect in the Thermal Cycling test and the samples met the following requirements, 1. Visual Inspection test. No Visual defects found 2. Maximum power determination, Power degradation≤5% 3. Insulation test- The measured insulation resistance was not less than 15.5 MΩ. For more details, please refer test report.
9	10.10	UV preconditioning		-		-	There was no evidence of a major defect in UV exposure and the samples met the following requirements, 1. Visual Inspection test. No Visual defects found 2. Maximum power determination, Power degradation≤5% 3. Insulation test- The measured insulation resistance was not less than 15.5 MΩ. For more details, please refer test report
10	10.9	Hot-spot endurance test					There was no evidence of a major visual defect in the Hotspot test and the samples met the following requirements, 1. Visual Inspection test. No Visual defects found 2. Maximum power determination, Power degradation≤5% 3. Insulation test- The measured insulation resistance was not less than 15.5 MΩ 4. Wet Leakage current test- The measured insulation resistance was not less than 15.5 MΩ. For more details, please refer test report
11	10.8	Outdoor exposure test	-	-	-	-	Test Not Applicable
12	10.7	Performance at low irradiance	-	-	-	-	Test Not Applicable
13	10.6	Performance at STC and NOCT	-	-	-	-	Test Not Applicable
14	10.5	Measurement of NOCT	-	-	-	-	Test Not Applicable
15	10.4	Measurement of temperature coefficients	-	-	-	-	Test Not Applicable

16	10.3	Insulation test	-	-	-	 All modules passed the test. For more details. Please refer test report.
17	10.2	Maximum power determination	-	-	-	- All Modules passed the test. Initial test date: 30/11/2022. Final test date: 23/02/2023. Please refer test report for more details
18	10.1	Visual inspection	-	-	-	- All the modules passed the visual inspection test. Test date: 02/11/2022. For more details, please refer to the test report
19	4	Marking	-	-	-	 All Markings are as per standard criteria. Please refer to the attached report for more information.

Vinay Singh
OIC Electrical
(Authorized Signatory)
Authorized on: 02 Aug, 2023 19:32 PM

Section Report No.: 22E1444N_1	IS 14286 (2010)
PART D. REMARKS	

please refer attached test report

Vinay Singh OIC Electrical (Authorized Signatory) Authorized on: 02 Aug, 2023 19:32 PM



Test Report issued under the responsibility of:



SUMMARY OF REPORT No. MCIND/2023/LB/049.V1, DATED (DD/MM/YYYY): 02/08/2023

ULR No. TC890623000000049F

(Number of pages in test report: Page no.3 to 95) TEST FORMAT AS PER IS 14286:2010 (First Revision)

TEST FORMAT AS PER IS 14286:2010 (First Revision)							
1. Name of manufacturer:	NOVASYS GREENERGY PRIVATE LIMITED						
2. Product:	Crystalline Silicon Terrestrial Photovoltaic						
	Modules (Si wafer based)						
3. Test Request Number:	SC22SPI00961						
4. Model:	Mono Crystalline (PERC):						
	NOVA550MP144 (Representative Model)						
	Series Models:						
	144 Half-cut Cell Family- 182mm Cell (1500V						
	System voltage):						
	NOVA545MP144, NOVA540MP144,						
	NOVA535MP144, NOVA530MP144,						
	NOVA525MP144, NOVA520MP144,						
	NOVA515MP144, NOVA510MP144,						
	NOVA505MP144, NOVA500MP144,						
	NOVA495MP144						
	132 Half-cut Cell Family- 182mm Cell (1500V						
	System voltage):						
	NOVA505MP132, NOVA500MP132,						
	NOVA495MP132, NOVA490MP132,						
	NOVA485MP132, NOVA480MP132,						
	NOVA475MP132, NOVA470MP132,						
	NOVA465MP132, NOVA460MP132,						
	NOVA455MP132						
	120 Half-cut Cell Family- 182mm Cell (1500V						
	System voltage):						
	NOVA460MP120, NOVA455MP120,						
	NOVA450MP120, NOVA445MP120,						
	NOVA440MP120, NOVA435MP120,						
	NOVA430MP120, NOVA425MP120,						
	NOVA420MP120, NOVA415MP120						
	108 Half-cut Cell Family- 182mm Cell (1500V						
	System voltage):						
	NOVA415MP108, NOVA410MP108,						
	NOVA405MP108, NOVA400MP108,						
	NOVA395MP108, NOVA390MP108,						
	NOVA385MP108, NOVA380MP108,						
	NOVA375MP108						
	96 Half-cut Cell Family- 182mm Cell (1500V						
	System voltage):						
	NOVA365MP96, NOVA360MP96,						
	NOVA355MP96, NOVA350MP96,						
	NOVA345MP96, NOVA340MP96,						





Solar PV Laboratory

TC-8906 ULR No : TC890623000000049F	Report No.: MCIND/2023/LB/049.V1
	NOVA COENTROS NOVA COENTROS

	JLR No : 1C890623000000049F	Report No.: MCIND/2023/LB/049.V1			
		NOVA335MP96, NOVA330MP96,			
		NOVA325MP96			
		72 Half-cut Cell Family- 182mm Cell (1500V			
		System voltage):			
		NOVA275MP72, NOVA270MP72,			
		NOVA265MP72, NOVA260MP72,			
		NOVA255MP72, NOVA250MP72,			
		NOVA245MP72			
l	Model differences provided	Yes			
	(if applicable): Yes/No				
l	Model differences verified as per MNRE	Yes			
	Guidelines for series formulation:				
	es/No				
7. T	est Results:				
SL.NO.	TEST REQUIREMENTS	CLAUSE	VERDICT		
1	Visual Inspection	10.1	Р		
2	Maximum Power Determination	10.2	Р		
3	Insulation Test	10.3	Р		
4	Hotspot Endurance Test	10.9	Р		
5	UV preconditioning	10.10	Р		
6	Thermal Cycling Test	10.11	Р		
7	Humidity Freeze Test	10.12	Р		
8	Damp Heat Test	10.13	Р		
9	Robustness and Termination Test	10.14	Р		
10	Wet Leakage Test	10.15	Р		
11	Mechanical Load Test	10.16	Р		
12	Hail Test	10.17	Р		
13	Bypass Diode Thermal Test	10.18	Р		

General Information:

1. The conformity certificates of critical components are verified to ensure complete testing of product under test and details regarding harmonized IEC/UL Standards (where IS standards are not available) are also provided in the list of critical component.

CONCLUSION:

- 1. Sample meets all relevent requirements of IS 14286:2010 (First Revision):
- 2. Sample fails to meet the following test requirements:

I, hereby, undertake that the verdict stated in the test reports for all the tests matches with the test results. The sample meets all relevant requirements of IS 14286:2010: /does not meet the requirementsstated above at 2) of conclusion. If any deviation is found, suitable punitive action may be taken by BIS.

(Signature of authorized person)

Asim Bisague

Date (DD/MM/YYYY): 02/08/2023